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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



Applicant(s): Vaez-Iravahi et al.  
 Assignee: KLA-Tencor Corporation  
 Title: Improved Sample Inspection System  
 Application No.: 10/070,079 Filing Date: March 1, 2002  
 Examiner: Not Known Group Art Unit: Not Known  
 Docket No.: TNCR.152US2 (Formerly: M-10670-5P US) Conf. No.: Not Known

September 9, 2003

Commissioner for Patents  
 P.O. Box 1450  
 Alexandria, VA 22313-1450


**REQUEST FOR STATUS OF APPLICATION**

Sir:

Applicant(s) hereby request a report on the status of the above-identified patent application. If a telephone call would expedite this request, please call Attorney for Applicant(s) shown below at (415) 318-1160.

Express Mail Label No.:  
 EV 321717259 US

Respectfully submitted,

  
 James S. Hsueh  
 Reg. No. 29,545